


<b>Search Notes</b>  	<b>Application/Control No.</b>  10596294	<b>Applicant(s)/Patent Under Reexamination</b>  WAKIYAMA, KOJI
	<b>Examiner</b>  Jason Heidemann	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
348	61,77,78,207.99,207.1,156	10/14/2009	/JEH/
340	5.2,5.52,5.53,5.8,5.82,5.83,540,426.1	10/14/2009	/JEH/
351	200,205,206,209	10/14/2009	/JEH/
382	100,115,117,118	10/14/2009	/JEH/
396	155,14,18,	10/14/2009	/JEH/
713	182,185,186	10/14/2009	/JEH/

SEARCH NOTES		
Search Notes	Date	Examiner
Searched Class and Subclass with Keywords (iris, focus, authentication, etc)	10/14/2009	/JEH/
Searched Google, ACM, and IEEE with keywords (iris focus, multiple focus ranges, etc)	10/14/2009	/JEH/
Author Search conducted on East	10/14/2009	/JEH/
Author Search Conducted on Google, ACM, and IEEE	10/14/2009	/JEH/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/Jason Heidemann/ Examiner.Art Unit 2624	10/14/2009
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